

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Attorney Docket No. 035924-0103

In re patent application of

Nobuo KOCHI et al.

Serial No.: 10/086,625

Filed: March 4, 2002

For: AN ELECTRON BEAM DEVICE AND METHOD FOR STEREOSCOPIC
MEASUREMENTS

PRELIMINARY AMENDMENT

Commissioner for Patents
Washington, D.C. 20231

Sir:

Prior to examination of the above-identified application, Applicant respectfully request that the following amendment be entered into the application:

IN THE TITLE:

Please change the title to read as follows:

--AN ELECTRON BEAM DEVICE AND METHOD FOR STEREOSCOPIC
MEASUREMENTS--

IN THE SPECIFICATION:

Page 11, the paragraph at lines 2 through 4, please replace with the following:

--FIGs. 1(A) and 1(B) illustrate to explain pictures taken at specified tilt angles of an object, a pattern of three straight lines of the identical length, placed at equal intervals--

Page 11, the paragraph at lines 5 through 6, please replace with the following:

--FIGs. 2(A) and 2(B) illustrate to explain three-dimensional images obtained by rectification of the tilted images shown in FIGs. 1(A) and 1(B).--

Page 11, the paragraph at lines 10 through 11, please replace with the following:

--FIGs. 4(A), 4(B), and 4(C) illustrate to explain reference marks formed on a specimen or a reference template.--

Page 11, the paragraph at lines 23 through 25, please replace with the following:

--FIGs. 12(A) and 12(B) show differential operators for the process of sharpening an image of 3 x 3 pixels.--

REMARKS

Entry of the foregoing amendments prior to examination is respectfully requested. A marked-up version of the amended title and paragraphs, showing the changes made, are attached.

Respectfully submitted,

JUN 11 2002
Date


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VERSIONS WITH MARKINGS TO SHOW CHANGES MADE

In the title:

AN ELECTRON BEAM DEVICE AND METHOD FOR [STEREOSCOPIC] STEREOGRAPHIC MEASUREMENTS

Page 11, the paragraph at lines 2 through 4:

[FIG. 1 illustrates] FIGS. 1(A) and 1(B) illustrate to explain pictures taken at specified tilt angles of an object, a pattern of three straight lines of the identical length, placed at equal intervals.

Page 11, the paragraph at lines 5 through 6:

[FIG. 2 illustrates] FIGs. 2(A) and 2(B) illustrate to explain three-dimensional images obtained by rectification of the tilted images shown in FIGs. 1(A) and 1(B).

Page 11, the paragraph at lines 10 through 11:

[FIG. 4 illustrates] FIGs. 4(A), 4(B), and 4(C) illustrate to explain reference marks formed on a specimen or a reference template.

Page 11, the paragraph at lines 23 through 25:

[FIG. 12 shows] FIGs. 12(A) and 12(B) show differential operators for the process of sharpening an image of 3 x 3 pixels.